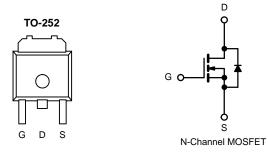


FDD390N15ALZ-VB Datasheet

N-Channel 150 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)		
150	0.074 at V_{GS} = 10 V	25.4	23 nC		
150	0.077 at V _{GS} = 8 V	22.5	23110		



FEATURES

- Halogen-free According to IEC 61249-2-21
 Definition
- Extremely Low Q_{gd} for Switching Losses
- 100 % Rg Tested
- 100 % Avalanche Tested
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

• Primary Side Switch



HALOGEN

Available

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	150	V	
Gate-Source Voltage		V _{GS}	± 20	V	
	T _C = 25 °C		25.4		
Continuous Drain Current (T 150 °C)	T _C = 70 °C		23.1		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	15.5 ^{b, c}		
	T _A = 70 °C		14.5 ^{b, c}	Α	
Pulsed Drain Current		I _{DM}	50	A	
Continuous Source-Drain Diode Current	T _C = 25 °C		4.5		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	2.6 ^{b, c}		
Single Pulse Avalanche Current	se Avalanche Current L = 0.1 mH		20		
Single Pulse Avalanche Energy	L = 0.1 mm	E _{AS}	20	mJ	
	T _C = 25 °C		5.9		
Maximum Power Dissipation	T _C = 70 °C	P _D	3.8	w	
	T _A = 25 °C		3.1 ^{b, c}	vv	
	T _A = 70 °C		2 ^{b, c}		
Operating Junction and Storage Temperature	T _J , T _{stg}				

THERMAL RESISTANCE RATINGS						
	Symbol	Typical	Maximum	Unit		
t ≤ 10 s	R _{thJA}	33	40	°C/W		
Steady State	R _{thJF}	17	21			
		$t \le 10 \text{ s}$ R_{thJA}	$t \le 10 \text{ s}$ R_{thJA} 33	t \leq 10 s R _{thJA} 33 40		

Notes:

a. Based on T_C = 25 °C.

b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under steady state conditions is 80 °C/W.

SPECIFICATIONS (T _J = 25 °C	unless othe	erwise noted)					
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static			•		•		
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	150			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		172		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 250 \mu A$		- 10			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1.5		3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 150 V, V _{GS} = 0 V V _{DS} = 120 V, V _{GS} = 0 V, T _J = 55 °C			1 10	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 10 \text{ V}, V_{GS} = 10 \text{ V}$	30		10	A	
	·D(on)	$V_{GS} = 10 \text{ V}, $	00	0.074			
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 8 \text{ V}, I_D = 5 \text{ A}$	0.074			Ω	
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 15 \text{ V}, \text{ I}_{D} = 5 \text{ A}$		23		S	
Dynamic ^b	013						
Input Capacitance	C _{iss}			1735		1	
Output Capacitance	C _{oss}	V _{DS} = 50 V, V _{GS} = 0 V, f = 1 MHz		160		pF	
Reverse Transfer Capacitance	C _{rss}	20 00		37		1	
Total Gate Charge	Q _g	V_{DS} = 75 V, V_{GS} = 10 V, I_D = 5 A		28.5	43		
ç	° °			23	35	nC	
Gate-Source Charge	Q _{gs}	$V_{DS} = 75$ V, $V_{GS} = 8$ V, $I_{D} = 5$ A		8			
Gate-Drain Charge	Q _{gd}			6.5			
Gate Resistance	R _g	f = 1 MHz		0.85	1.3	Ω	
Turn-on Delay Time	t _{d(on)}			14	21		
Rise Time	t _r	$V_{DD} = 50 \text{ V}, \text{ R}_{L} = 10 \Omega$		12	18	-	
Turn-Off Delay Time	t _{d(off)}	${\rm I_D} \cong 5 \; {\rm A}, {\rm V_{GEN}} = 10 \; {\rm V}, {\rm R_g} = 1 \; \Omega$		22	33		
Fall Time	t _f			6	10	ns	
Turn-On Delay Time	t _{d(on)}			16	24	-	
Rise Time	t _r	$V_{DD} = 50 \text{ V}, \text{ R}_{L} = 10 \Omega$		12	18		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 8 \text{ V}, R_g = 1 \Omega$		20	30		
Fall Time	t _f			7	12		
Drain-Source Body Diode Characteristi		T 05 00				1	
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			7.7	A	
Pulse Diode Forward Current ^a	I _{SM}			0.77	50		
Body Diode Voltage	V _{SD}	I _S = 2.6 A		0.77	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			63	95	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 5 A, dI/dt = 100 A/μs, T _{.I} = 25 °C		110	165	nC	
Reverse Recovery Fall Time	t _a			49		ns	
Reverse Recovery Rise Time	t _b			14		-	

Notes:

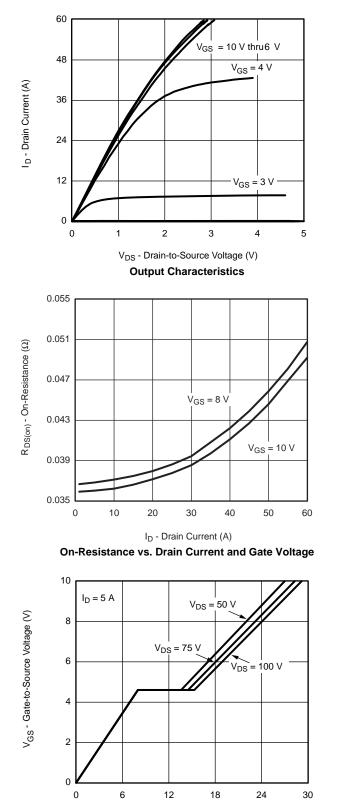
a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%$

a. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

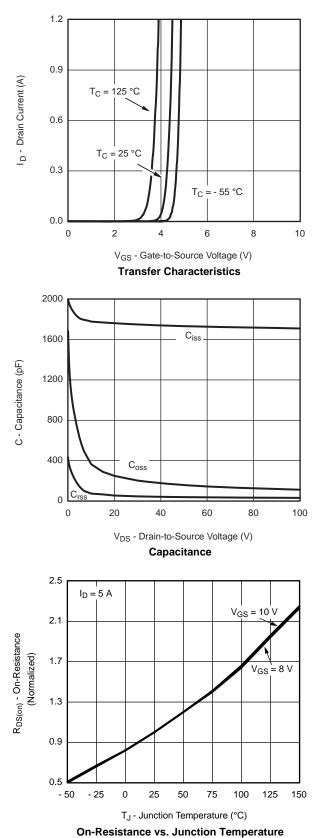
VBsemi Bsemi.com



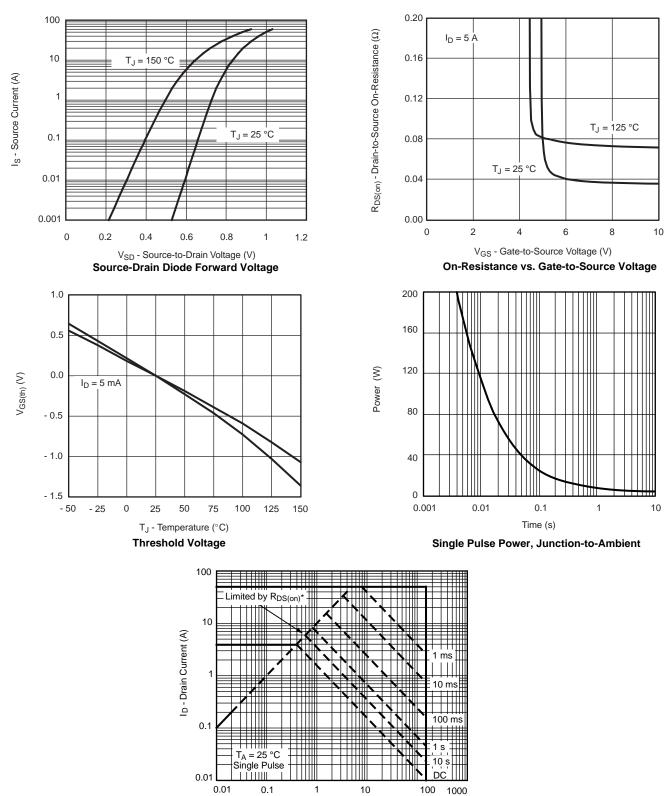


Q_g - Total Gate Charge (nC) Gate Charge

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





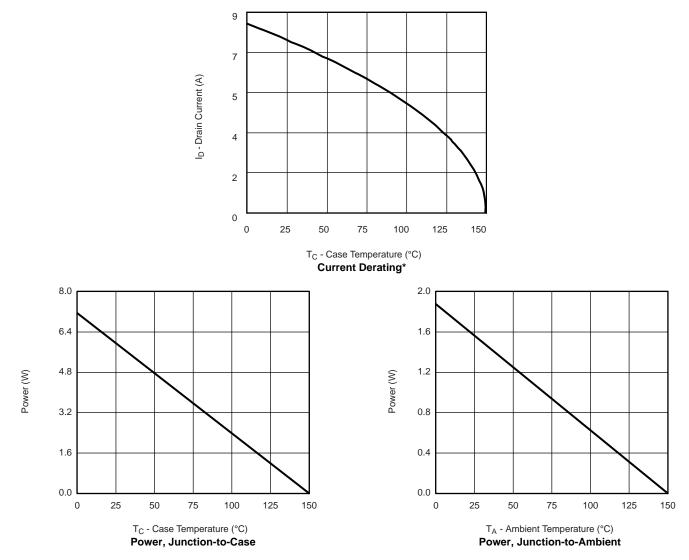


 $\label{eq:VDS} V_{DS} \mbox{-} Drain-to-Source Voltage (V) $$ V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified $$ Safe Operating Area, Junction-to-Ambient $$$

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



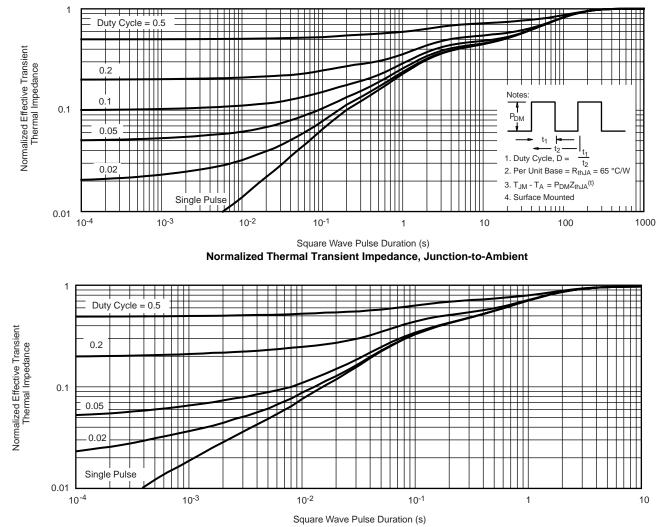
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



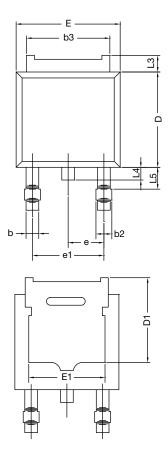
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

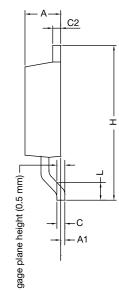


Normalized Thermal Transient Impedance, Junction-to-Foot



TO-252AA CASE OUTLINE





	MILLIN	IETERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
А	2.18	2.38	0.086	0.094
A1	-	0.127	-	0.005
b	0.64	0.88	0.025	0.035
b2	0.76	1.14	0.030	0.045
b3	4.95	5.46	0.195	0.215
С	0.46	0.61	0.018	0.024
C2	0.46	0.89	0.018	0.035
D	5.97	6.22	0.235	0.245
D1	5.21	-	0.205	-
Е	6.35	6.73	0.250	0.265
E1	4.32	-	0.170	-
Н	9.40	10.41	0.370	0.410
е	2.28 BSC		0.090 BSC	
e1	4.56 BSC		0.180 BSC	
L	1.40	1.78	0.055	0.070
L3	0.89	1.27	0.035	0.050
L4	-	1.02	-	0.040
L5	1.14	1.52	0.045	0.060
ECN: X12- DWG: 534	0247-Rev. M, 7	24-Dec-12		

Note

• Dimension L3 is for reference only.



RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)



Recommended Minimum Pads Dimensions in Inches/(mm)



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